

<b>Notice of References Cited</b>	Application/Control No. 10/046,175	Applicant(s)/Patent Under Reexamination WATANABE, YOSHIAKI	
	Examiner Ryan F Pitaro	Art Unit 2174	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
	A	US-6,182,094 B1	01-2001	Humpleman et al.	715/513
	B	US-6,583,799 B1	06-2003	Manolis et al.	715/838
	C	US-2002/0077829 A1	06-2002	Brennan et al.	704/275
	D	US-6,828,992 B1	12-2004	Freeman et al.	715/810
	E	US-6,429,882 B1	08-2002	Abdelnur et al.	715/763
	F	US-6,785,822 B1	08-2004	Sadhwani-Tully, Bharati Hemandas	713/201
	G	US-6,788,313 B1	09-2004	Heil, Scott Martin	715/745
	H	US-6,266,060 B1	07-2001	Roth, Steven William	715/853
	I	US-2002/0093523 A1	07-2002	Ashe et al.	345/700
	J	US-6,483,523 B1	11-2002	Feng, Ming-Whei	715/745
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N				
	O				
	P				
	Q				
	R				
	S				
	T				

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U
	V
	W
	X

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.